

# 1N 5712

## SMALL SIGNAL SCHOTTKY DIODE

DO 35

(Glass)

#### DESCRIPTION

Metal to silicon junction diode featuring high breakdown voltage, low turn-on voltage and ultrafast switching.

Primarly intended for high level UHF/VHF detection and pulse application with broad dynamic range.

#### **ABSOLUTE RATINGS** (limiting values)

Symbol	Parameter	Value	Unit	
V <sub>RRM</sub>	Repetitive Peak Reverse Voltage		20	V
IF	Forward Continuous Current* $T_a = 25 \ ^{\circ}C$		35	mA
Ptot	Power Dissipation* $T_a = 25^{\circ}C$		430	mW
T <sub>stg</sub> Tj	Storage and Junction Temperature Range	- 65 to 200	°C	
TL	Maximum Lead Temperature for Soldering during 10s at 4mm from Case		230	°C

#### THERMAL RESISTANCE

Symbol	Test Conditions	Value	Unit
R <sub>th(j-a)</sub>	Junction-ambient*	400	°C/W

#### **ELECTRICAL CHARACTERISTICS**

#### STATIC CHARACTERISTICS

Symbol	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>BR</sub>	$T_{amb} = 25^{\circ}C$ $I_R = 10\mu A$	20			V
V <sub>F</sub> * *	$T_{amb} = 25^{\circ}C$ $I_F = 1mA$			0.41	V
	$T_{amb} = 25^{\circ}C$ $I_F = 35mA$			1	
I <sub>R</sub> * *	$T_{amb} = 25^{\circ}C$ $V_R = 15V$			0.1	μΑ

### DYNAMIC CHARACTERISTICS

Symbol		Test Conditio	ons	Min.	Тур.	Max.	Unit
С	$T_{amb} = 25^{\circ}C$	$V_R = 0V$	f = 1MHz			1.2	pF
τ	$T_{amb} = 25^{\circ}C$	I <sub>F</sub> = 5mA	Krakauer Method			100	ps

\* On infinite heatsink with 4mm lead length

\*\* Pulse test:  $t_p \le 300 \mu s \ \delta < 2\%$ .

Matched batches available on request. Test conditions (forward voltage and/or capacitance) according to customer specification.

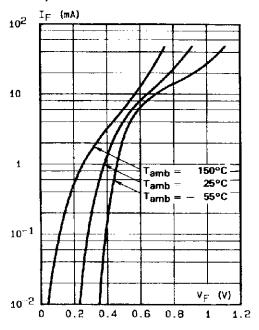


Figure 1. Forward current versus forward voltage at different temperatures (typical values).

Figure 3. Reverse current versus ambient temperature.

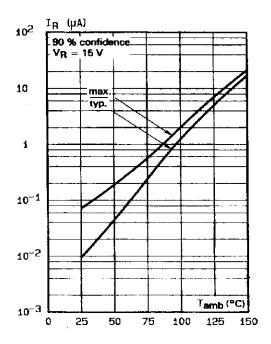


Figure 2. Forward current versus forward voltage (typical values).

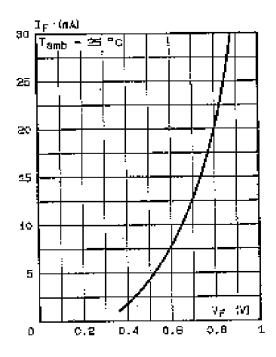
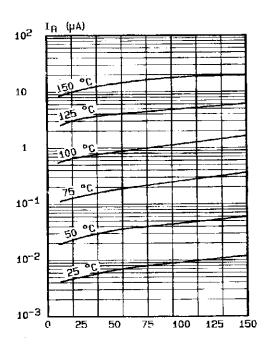
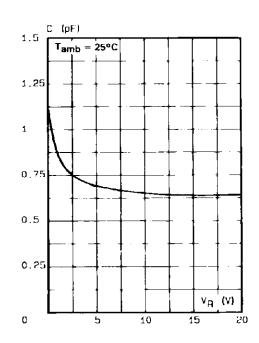


Figure 4. Reverse current versus continuous
reverse voltage (typical values).





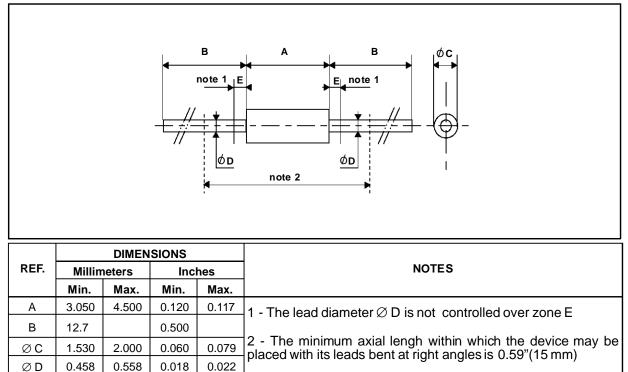


# Figure 5. Capacitance C versus reverse applied voltage $V_{\text{R}}$ (typical values).



### PACKAGE MECHANICAL DATA

#### DO 35 Glass



Cooling method : by convection and conduction Marking: clear, ring at cathode end. Weight: 0.15g

1.27

0.050

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